



Automatic Testing Equipment







Max. 100 times/sec High-speed Inspection



Model 1118 INTEGRATED HITESTER offers high speed inspection that is ideal for IC package components such as FC-PGA, FC-BGA and MCM substrates. The high-precision fine-pitch probing is made up of two flying probes from the top side, which operates together with the lower test head/fixture to provide super speed inspection while maintaining low running costs. In addition to the short/open inspection feature and insulation testing for up to 250VDC, a 4-terminal resistance measurement function is also standardly equipped, demonstrating that the unit is powerful for also testing of low resistance of IVH (Interstitial Via Hole).



http://www.hioki.co.jp/

HIOKI company overview, new products, environmental considerations and other information are available on our website.

■ Specifications

[Measuring unit]

Data types : Step data

S/O data (Net data)

Number of channels: Test heads: Standard 512 channels

(maximum 4,096 channels)

Flying unit: 2-channel External electrode: 4-channel

: 400mΩ~: Detecting short Continuity test

100 μ Ω~: Measuring resistance : ~500MΩ/250V Insulation test

 ${\sim}200M\Omega/100V$

(variable in steps of 1 V)

DC measurement

: $400\mu\Omega$ to $40M\Omega$ Resistance Capacitance : 4μ F to 400mF AC measurement (flying probe unit only) : 100Ω to $100M\Omega$ Resistance : 10fF to 10µF Capacitance : $10\mu H$ to 100HInductance

■ Test types

Test type	Test item
Tests for conductivity	Continuity test
	Step test
	Rubber test*
Tests for insulation	Insulation test 1**
	Insulation test 2**
Tests for Component	Step test

^{* :}With an optional conductive rubber unit.

■ Testable Boards

Board size : 10×10-70×250mm **Board thickness** : 0.3-3.2mm

[Mechanism part]

■ Flying Probe Unit

Number of arms : Two arms (L, R) Work area · 70×70 mm Range of XY movement : $300 \times 100 \text{ mm}$

Probing accuracy: Within ±50µm (each arm X-Y directions)

(20°C±3°C)

Repeatability of : Within $\pm 20\mu m$ (probing position) movement (at the same temperature)

Minimum pitch of : 0.1mm

probes (between the left and right arms when using a

■ Positioning Correction : Automatic positioning correction

link-type probe)

■ Test Heads

Probing area : 10×10-70×70mm Maximum number of probes: 1024

Minimum pitch : 4-terminal measurement probes: 1.0 mm

Fine pitch probes: 0.2 mm

■ Test Head Elevating Unit

Maximum installed test heads: 2 (A, B) with a double shuttle system

Probing accuracy $\,: Within \, \pm 100 \mu m$ Repeatability: Within $\pm 20 \mu m$

■ Transport Unit

Number of board transport shuttles: 2 (A, B): Double shuttle

Repeatability: Within ±5µm

[General specifications] -

Power supply voltage : 200/220 VAC single-phase (50/60 Hz) :

Specify at time of shipment

Consumption power : 3kVA

Operating temperature : 23°C±10°C 70%rh max.(with no condensation)

and humidity range

Storage temperature $:10^{\circ}\text{C} \text{ to }43^{\circ}\text{C }80\% \text{ rh } \text{max}.$ and humidity range (with no condensation): Main unit

23°C±10°C 70%rh max.

(with no condensation): Test heads

Location for use

: Room: Do not operate in a dusty environment,

an area subject to vibration, an atmosphere

containing corrosive gas, or the like Floor strength: At least 500 kg/m²

: 0.5 to 0.99 Mpa (dry air)

Applied air Air consumption : Up to 0.3 Nl/min

Dimensions : Approx. 1260 (W) × 1750 (H) × 1245 (D) mm

(excluding protruding parts)

Mass : Approx. 1000 kg

1118 X-Y INTEGRATED HITESTER

■ Factory Options

1165-04 TEST HEAD 1138-01 SCANNER BOARD

1139-04 1118 DATA COMPOSITION SOFTWARE

1330-04 MEASUREMENT UNIT CALIBRATION UNIT

1355-01 VACUUM PUMP

MAINTENANCE TOOL SET 1356

1941-31 STAMP UNIT for R ARM 1941-32 STAMP UNIT for L ARM

1944-01 EXTENSION I/O BOARD 1946-04 MONITOR CAMERA

1947-21 1.2 POWER LENS UNIT for R ARM 1947-22 1.2 POWER LENS UNIT for L ARM 1948-11 CONDUCTIVE RUBBER UNIT

1139-53 FL-LINK5 FLY-LINE LINK SOFTWARE

Options

1134-02 IMPRESSION SHEET

(1 box supplied as standard accessory)

1164-02 ONE-WAY CLUTCH

(Used for installatio absorbing probes) tion and removal of shock-

1164-03 PROBE ATTACHMENT

(Used during installation of shock-absorbing probes)

PRINTER PAPER

1196

1350-03 OFFSET BOARD (2 boards supplied as standard accessories)

1172-66 LINK PROBE

1172-67 DOUBLE LINK PROBE

1172-68 LINK PROBE WITH BLADE 1172-69 DOUBLE LINK PROBE WITH BLADE

1172-70 SHOCK-ABSORBING SINGLE NEEDLE PROBE (SK)*

1172-71 SHOCK-ABSORBING SINGLE NEEDLE

PROBE (WC)*

1172-72 SHOCK-ABSORBING TRIANGULAR PYRAMID PROBE (SK)*

1172-74 PROBE FOR CALIBRATION

1172-75 SHOCK-ABSORBING SINGLE NEEDLE PROBE (HP)

1172-76 SHOCK-ABSORBING SINGLE NEEDLE PROBE (HP SR10)*

1172-77 SHOCK-ABSORBING SINGLE NEEDLE PROBE (WC SR10)*

1172-80 PROBE (Flat spring, 3 mm stroke) 1172-81 LINK PROBE (Link, high-speed version)

1172-83 DOUBLELINK PROBE

(Double link, 35 um between terminals) *: The 1164-03 PROBE ATTACHMENT is necessary.

DISTRIBUTED BY

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^{**:} Tset conditions for the insulation test 1 and 2 can be set separately.